SDLS043

DECEMBER 1983 - REVISED MARCH 1988

- D-C Triggered from Active-High or Active-Low Gated Logic Inputs
- Retriggerable for Very Long Output Pulses, Up to 100% Duty Cycle
- Overriding Clear Terminates Output Pulse
- '122 and 'LS122 Have Internal Timing Resistors

description

These d-c triggered multivibrators feature output pulse-duration control by three methods. The basic pulse time is programmed by selection of external resistance and capacitance values (see typical application data). The '122 and 'LS122 have internal timing resistors that allow the circuits to be used with only an external capacitor, if so desired. Once triggered, the basic pulse duration may be extended by retriggering the gated low-level-active (A) or high-level-active (B) inputs, or be reduced by use of the overriding clear. Figure 1 illustrates pulse control by retriggering and early clear.

The 'LS122 and 'LS123 are provided enough Schmitt hysteresis to ensure jitter-free triggering from the B input with transition rates as slow as 0.1 millivolt per nanosecond.

The Rint in nominal 10 k Ω for '122 and 'LS122.

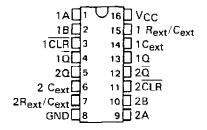
SN54122, SN54LS122...J OR W PACKAGE SN74122...N PACKAGE SN74LS122...D OR N PACKAGE (TOP VIEW) (SEE NOTES 1 THRU 4)

$\overline{}$	<u>t</u>
U 14	□vcc
13	Rext/Cext
12	DNC
7.1	□ c _{ext}
10	□ NC
9	Rint
8	βa
	13 12 11 10

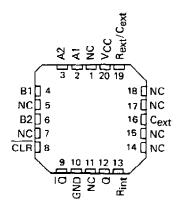
NOTES: 1. An external timing capacitor may be connected between Cext and Rext/Cext (positive).

- To use the internal timing resistor of '122 or 'LS122, connect Rint to VCC.
- For improved pulse duration accuracy and repeatability, connect an external resistor between R_{ext}/Ce_{xt} and V_{CC} with R_{int} open-circuited.
- To obtain variable pulse durations, connect an external variable resistance between R_{int} or R_{ext}/C_{ext} and VCC.

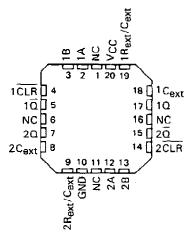
SN54123, SN54130, SN54LS123... J OR W PACKAGE SN74123. SN74130... N PACKAGE SN74LS123... D OR N PACKAGE (TOP VIEW) (SEE NOTES 1 THRU 4)



SN54LS122 . . . FK PACKAGE (TOP VIEW) (SEE NOTES 1 THRU 4)



SN54LS123 . . . FK PACKAGE (TOP VIEW) (SEE NOTES 1 THRU 4)



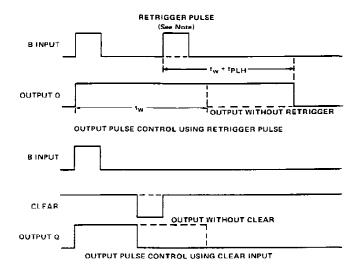
NC - No internal connection

PRODUCTION DATA documents contain information current as of publication data. Products conform to specifications per the terms of Texas Instruments standard warrenty. Production processing does not necessarily include testing of all parameters.



SN54122, SN54123, SN54130, SN54LS122, SN54LS123, SN74122, SN74123, SN74130, SN74LS122, SN74LS123 RETRIGGERABLE MONOSTABLE MULTIVIBRATORS

description (continued)



NOTE: Retrigger pulses starting before 0.22 C_{ext} (in picofrads) nanoseconds after the initial trigger pulse will be ignored and the output duration will remain unchanged.

FIGURE 1-TYPICAL INPUT/OUTPUT PULSES

'122, 'LS122 FUNCTION TABLE

	INP	ZTL			OUT	UTS
CLEAR	Α1	A2	81	82	a	ā
L	х	×	Х	×	L	Н
x	н	н	Х	х	L†	нŤ
×	×	×	Ł	х	LŤ	нŤ
×	×	×	×	L	LŤ	нŤ
н	L	X	Ť	Н	л	П
н	L	х	н	1	ıπ	U,
н	х	L	Ť	н	л	U
н	x	L	н	1	л	IJ
н	H	1	н	Н	л	U
н	1	ż	Н	н	л	U
Н	1	н	Н	Н	П	U
1	L	×	Н	Η.	л	ᅚ
t	х	L	н	н	7.	v

123, 130, LS123

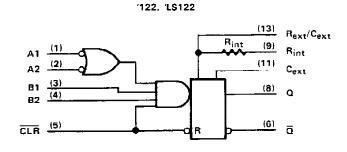
INP	JTS		OUT	PUTS
CLEAR	Α	В	a	ā
L	×	X	L	Н
×	Н	х	L†	нŤ
×	x	L	_†	нŤ
н	Ł	t	л	IJ
н	ţ	н	л	T
1	L	н :	л.	v

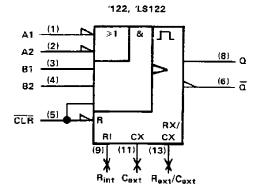
See explanation of function tables on page

T These lines of the functional tables assume that the indicated steady-state conditions at the A and B inputs have been set up long enough to complete any pulse started before the set up.

logic diagram (positive logic)

logic symbol[†]



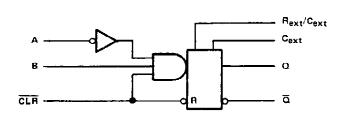


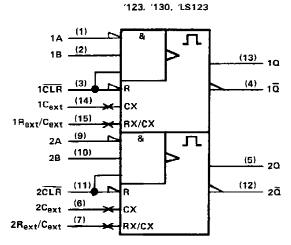
 R_{int} is nominally 10 $k\Omega$ for '122 and 'LS122

logic diagram (positive logic) (each multivibrator)

'123, '130, 'LS123

logic symbol†



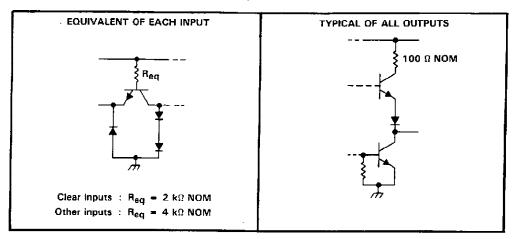


Pin numbers shown are for D, J, N, and W packages.

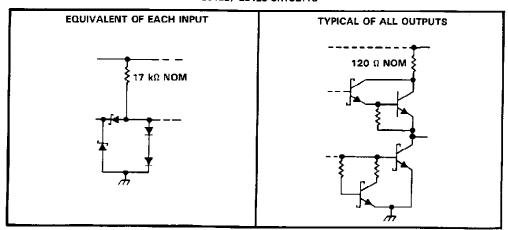
[†]These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

schematics of inputs and outputs

'122, '123, '130 CIRCUITS



'LS122, 'LS123 CIRCUITS



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7	V
Input voltage: '122, '123, '130	5.5	V
'LS122, 'LS123	7	٧
Operating free-air temperature range: SN54'55°C to	125	°C
SN74'	701	°C
Storage temperature range65°C to	150	°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN54122, SN54123, SN54130, SN74122, SN74123, SN74130 RETRIGGERABLE MONOSTABLE MULTIVIBRATORS

recommended operating conditions

	SN54'			1	UNIT		
	MIN	NOM	MAX	MIN	NOM	MAX	ו וואט
Supply voltage, VCC	4.5	5	5.5	4.75	5	5.25	٧
High-level output current, IOH			-800			-800	μА
Law-level output current, IQL			16			16	mΑ
Pulse duration, tw	40			40			ns
External timing resistance, R _{ext}	5	-	25	5		50	kΩ
External capacitance, C _{ext}	No	restrict	ian	No restriction		tion	
Wiring capacitance at Rext/Cext terminal	-		50			50	pΕ
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended free-air operating temperature range (unless otherwise noted)

			#F0+ 00	Neu-riobio+		122			'123 , <u>'</u> 13	30	UNIT
	PARAMETER		TEST CONDITIONS†		MIN	TYP#	MAX	MIN	TYP‡	MAX	UNII
VIH	High-level input voltage				2			2			V
VIL	Low-level input voltage						0.8			8,0	V
Vik	Input clamp voltage		V _{CC} = MIN,	l _f = –12 mA	-		-1.5			-1.5	V
VOH	High-level output voltage		V _{CC} = MIN, See Note 5	I _{OH} = -800 μA,	2.4	3.4		2.4	3.4		٧
VOL	Low-level output voltage		V _{CC} = MIN, See Note 5	IOL = 16 mA,		0,2	0.4		0.2	0,4	V
I ₁	Input current at maximum	input voltage	V _{CC} = MAX,	V _I = 5.5 V			1			1	mA
Чн	High-level input current	Data inputs Clear input	V _{CC} = MAX,	V _I = 2.4 V			40 80			40 80	μА
I _Ι Γ	Low-level input current	Data inputs Clear input	V _{CC} = MAX,	V = 0.4 V			-1.6 -3.2			-1.6 -3.2	mA
los	Short-circuit output current	§	V _{CC} = MAX,	See Note 5	-10		-40	-10		-40	mΑ
Icc	Supply current (quiescent o		VCC = MAX,	See Notes 6 and 7		23	36		46	66	mΑ

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTES: 5. Ground Cext to measure VOH at Q, VOL at Q, or IOS at Q, Cext is open to measure VOH at Q, VOL at Q, or IOS at Q.

6. Quiescent ICC is measured (after clearing) with 4.5 V applied to all clear and A inputs, B inputs grounded, all outputs open and $R_{ext} = 25 \text{ k}\Omega$. R_{int} of '122 is open.

7. ICC is measured in the triggered state with 2.4 V applied to all clear and B inputs, A inputs grounded, all outputs open, $C_{\text{ext}} = 0.02 \, \mu\text{F}$, and $R_{\text{ext}} = 25 \, \text{k}\Omega$. R_{int} of '122 is open.

switching characteristics, VCC = 5 V, TA = 25°C, see note 8

					,	122, '1	30		123		
PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN	TYP	MAX	MIN	TYP	MAX	UNIT	
	А		C _{ext} = 0, R _{ext} = C _L = 15 pF, R _L =			22	33		22	33	ns
tPLH t	В	Q				19	28		19	28	1115
	А	ā		B -510		30	40		30	40	
tPHL tPHL	8	u		$R_{ext} = 5 k\Omega$, pF, $R_1 = 400 \Omega$	-	27	36		27	36	ns
tPHL_		a		H L = 400 11		18	27		18	27	ns
¹PLH	Clear	Œ				30	40	l	30	40	115
twQ (min)	A or B	Ω				45	65		45	76	ns
twQ	A or B	Q.	C _{ext} = 1000 pF, C _L = 15 pF,	R_{ext} = 10 kΩ, R_L = 400 Ω	3.08	3.42	3.76	2.76	3.03	3,37	μς

 $[\]P_{tplH}$ = propagation delay time, low-to-high-level output

NOTE 8: Load circuits and voltage waveforms are shown in Section 1.



[‡] All typical values are at V_{CC} = 5 V, T_A = 25 °C.

Not more than one output should be shorted at a time.

 t_{PHL} = propagation delay time, high-to-low-level output t_{WQ} = duration of pulse at output Q.

SN54LS122, SN54LS123, SN74LS122, SN74LS123 RETRIGGERABLE MONOSTABLE MULTIVIBRATORS

recommended operating conditions

	SN54LS'				UNIT		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, VCC	4.5	5	5.5	4.75	5	5,25	V
High-level output current, IOH			-400			-400	μΑ
Low-level output current, IOL			4	ļ		8	mΑ
Pulse duration, tw	40			40			ns
External timing resistance, Rext	5		180	5		260	kΩ
External capacitance, Cext	No	restrict	ion	No	restrict	ion	
Wiring capacitance at Rext/Cext terminal			50			50	pF
Operating free-air temperature, TA	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		ST CONDITIONS†			SN54LS	S'		UNIT		
	PARAMETER	LEST COMPLITORS.			MIN	TYP#	MAX	MIN	TYP‡	MAX	UNII
VIH	High-level input voltage				2			2			V
VIL	Low-level input voltage						0.7			0.8	V
VIK	Input clamp voltage	VCC = MIN,	l = −18 mA				-1.5			-1.5	V _
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = V _{IL} max	V _{IH} = 2 V, I _{OH} = -400 μA		2.5	3,5	•	2.7	3.5	·	٧
VOL	Low-level output voltage	V _{CC} = MIN, V _{IL} = V _{IL} max	V _{IH} = 2 V,	I _{OL} = 4 mA		0.25	0.4		0.25 0.35	0.4 0.5	٧
l _l	Input current at maximum input voltage	V _{CC} = MAX,	V = 7 V				0.1			0,1	mΑ
11H	High-level input current	VCC = MAX.	V ₁ = 2.7 V		Ţ	·-	20			20	μА
IL	Low-level input current	V _{CC} = MAX,	V ₁ = 0.4 V				-0.4			 0.4	mΑ
los	Short-circuit output currents	V _{CC} = MAX	<u> </u>		-20		-100	-20		-100	mΑ
1CC	Supply current (quiescent or triggered)	VCC = MAX,	See Nate 13	'LS122 'LS123		6 12	11 20		6 12	11 20	mA

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

NOTES: 12. To measure V_{OH} at Q, V_{OL} at \overline{Q} , or I_{QS} at Q, ground R_{ext}/C_{ext}, apply 2 V to B and clear, and pulse A from 2 V to 0 V.

switching characteristics, VCC = 5 V, TA = 25°C (see note 8)

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CON	MIN	TYP	MAX	UNIT	
	A	a				23	33	
tPLH	B		23	44	лѕ			
	Ä		1 _	5 510		32	45	
tPHL -	В	"	C _{ext} = 0, C _L = 15 pF,	$R_{ext} = 5 k\Omega$, $R_{L} = 2 k\Omega$		34	56	ns
[†] PHL		Q	CL * 15 pF,	H_ = 2 KM		20	27	
tPLH .	Clear	ā				28	45	ns
t _{wQ} (min)	A or B	<u> </u>				116	200	ns
t _w Q	A or B	α	C _{ext} = 1000 pF, C _L = 15 pF,	$R_{ext} = 10 k\Omega$, $R_L = 2 k\Omega$	4	4.5	5	μs

 $f_{tpLH} = propagation delay time, low-to-high-level output$



 $^{^{\}ddagger}$ All typical values are at $^{\lor}$ CC = 5 V, $^{\lor}$ TA = 25 °C.

SNot more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

^{13.} With all outputs open and 4.5 V applied to all data and clear inputs. ICC is measured after a momentary ground, then 4.5 V, is applied to A or B inputs.

tpHL = propagation delay time, high-to-low-level output

 t_{WQ} = duration of pulse at output Q.

NOTE 8: Load circuits and voltage waveforms are shown in Section 1.

TYPICAL APPLICATION DATA FOR '122, '123, '130

For pulse durations when $C_{\text{ext}} \leq 1000$ pF, see Figure 4.

The output pulse duration is primarily a function of the external capacitor and resistor. For $C_{\text{ext}} > 1000 \text{ pF}$, the output pulse duration (t_{W}) is defined as:

$$t_W = K \cdot R_T \cdot C_{ext} \left(1 + \frac{0.7}{R_T} \right)$$

where

K is 0.32 for '122, 0.28 for '123 and '130

 $R_{\mbox{\scriptsize T}}$ is in $k\Omega$ (internal or external timing resistance.)

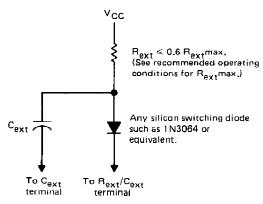
Cext is in pF

tw is in ns

To prevent reverse voltage across C_{ext} , it is recommended that the method shown in Figure 2 be employed when using electrolytic capacitors and in applications utilizing the clear function. In all applications using the diode, the pulse duration is:

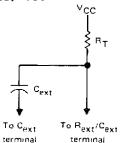
$$t_{W} = K_{D} \cdot R_{T} \cdot C_{ext} \left(1 + \frac{0.7}{R_{T}} \right)$$

KD is 0.28 for '122, 0.25 for '123 and '130



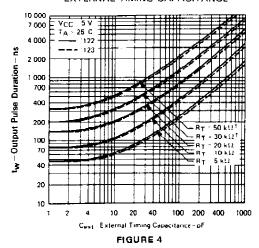
TIMING COMPONENT CONNECTIONS WHEN $C_{\text{ext}} \geq 1000 \text{ p F AND CLEAR IS USED}$ FIGURE 2

Applications requiring more precise pulse durations (up to 28 seconds) and not requiring the clear feature can best be satisfied with the '121.



TIMING COMPONENT CONNECTIONS FIGURE 3

TYPICAL OUTPUT PULSE DURATION vs EXTERNAL TIMING CAPACITANCE



[†]These values of resistance exceed the maximum recommended for use over the full temperature range of the SN54' circuits.

TYPICAL APPLICATION DATA FOR 'LS122, 'LS123

The basic output pulse duration is essentially determined by the values of external capacitance and timing resistance. For pulse durations when $C_{\rm ext} \leq 1000$ pF, use Figure 6, or use Figure 7 where the pulse duration may be defined as:

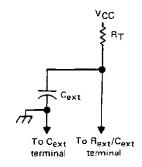
When $C_{ext} \ge 1 \mu F$, the output pulse width is defined as:

$$t_W = 0.33 \cdot R_T \cdot C_{ext}$$

For the above two equations, as applicable;

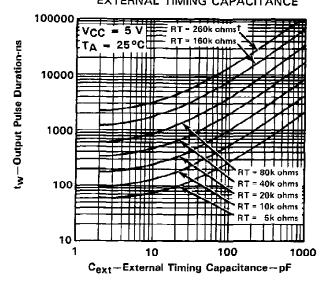
K is multiplier factor, see Figure 7 RT is in $k\Omega$ (internal or external timing resistance) C_{ext} is in pF t_{W} is in ns

For maximum noise immunity, system ground should be applied to the $C_{\rm ext}$ node, even though the $C_{\rm ext}$ node is already tied to the ground lead internally. Due to the timing scheme used by the 'LS122 and 'LS123, a switching diode is not required to prevent reverse biasing when using electolytic capacitors.



TIMING COMPONENT CONNECTIONS FIGURE 5

'LS122, 'LS123 TYPICAL OUTPUT PULSE DURATION vs EXTERNAL TIMING CAPACITANCE



[†]This value of resistance exceeds the maximum recommended for use over the full temperature range of the SN54LS circuits.

FIGURE 6



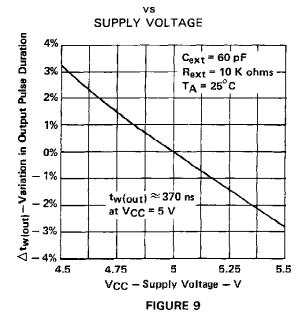
TYPICAL APPLICATION DATA FOR 'LS122, 'LS123[†]

EXTERNAL CAPACITOR (K IS INDEPENDENT OF R) O.0001 O.25 0.30 0.35 0.40 0.45 0.50 0.55 K – Multiplier Factor –

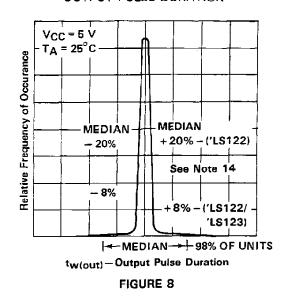
MULTIPLIER FACTOR

VARIATION IN OUTPUT PULSE DURATION

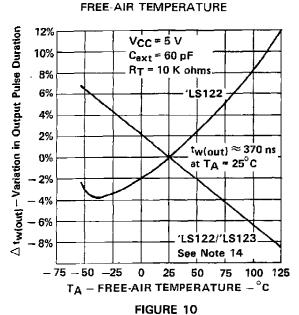
FIGURE 7



DISTRIBUTION OF UNITS
vs
OUTPUT PULSE DURATION



VARIATION IN OUTPUT PULSE DURATION vs



NOTE 14: For the 'LS122, the internal timing resistor, Rint was used. For the 'LS122/123, an external timing resistor was used for RT.

†Data for temperatures below 0°C and above 70°C and for suply voltages below 4.75 V and above 5.25 V are applicable for SN54LS122 and SN54LS123 only.

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1996, Texas Instruments Incorporated